between the test socket and the nest the electronic component can be pressed against, and lifted from, the test contacts of the test socket, characterised in that the at least one cleaning unit is designed in such a manner that during each test stroke the test contacts come into contact with the at least one cleaning unit, wherein the at least one cleaning unit is mounted in such a manner that it moves together with the nest, wherein the at least one cleaning unit is mounted to the nest or to a stamp that moves the nest.

According to another embodiment of the invention, there is provided a device for testing electronic components with at least one test socket with test contacts, with a nest in which at least one electronic component can be placed, and with at least one cleaning unit for the test contacts of the test socket, wherein by means of a relative movement, which can be carried out as a test stroke, between the test socket and the nest the electronic component can be pressed against, and lifted from, the test contacts of the test socket, wherein the at least one cleaning unit is designed in such a manner that during each test stroke the test contacts come into contact with the at least one cleaning unit, wherein the at least one cleaning unit is movably attached to the test socket.

According to the invention, the object is met by a device for testing electronic components, which device comprises the features of claim 1. Because the at least one cleaning unit is designed in such a manner that during each test stroke the test contacts come into contact with the at least one cleaning unit, the test contacts are cleaned before and/or after each test, and consequently

Claims

1. A device for testing electronic components with at least one test socket with test contacts, with a nest in which at least one electronic component can be placed, and with at least one cleaning unit for the test contacts of the test socket, wherein by means of a relative movement, which can be carried out as a test stroke, between the test socket and the nest the electronic component can be pressed against, and lifted from, the test contacts of the test socket, characterised in that
the at least one cleaning unit is designed in such a manner that during each test stroke the test contacts come into contact with the at least one cleaning unit, wherein the at least one cleaning unit is mounted in such a manner that it moves together with the nest, wherein the at least one cleaning unit is mounted to the nest or to a stamp that moves the nest.

2. The device as set forth in claim 1, characterised in that
the electronic component is fixed in the nest by means of a holding element, and in that the at least one cleaning unit is fixed to the holding element.

3. The device as set forth in any one of claims 1 to 2, characterised in that the at least one cleaning unit comprises a basic body and at least one contact module.

4. The device as set forth in claim 3, characterised in that
the at least one contact module comprises bristles.

5. The device as set forth in claim 3, characterised in that
the at least one contact module comprises an elastic plastic material, wherein a surface of the at least one contact module, which surface cleans the test contacts, has a predetermined roughness.

6. The device as set forth in any one of claims 1 to 5, characterised in that
the at least one cleaning unit is exchangeable.

7. The device as set forth in any one of claims 3 to 6, characterised in that the at least one contact module is exchangeable.

8. A device for testing electronic components with at least one test socket with test contacts, with a nest in which at least one electronic component can be placed, and with at least one cleaning unit for the test contacts of the test socket, wherein by means of a relative movement, which can be carried out as a test stroke, between the test socket and the nest the electronic component can be pressed against, and lifted from, the test contacts of the test socket, characterised in that
the at least one cleaning unit is designed in such a manner that during each test stroke the test contacts come into contact with the at least one cleaning unit, wherein the at least one cleaning unit is movably attached to the test socket.

9. The device as set forth in claim 8, characterised in that
the at least one cleaning unit is movable towards the test socket against the force of an elastic element.

10. The device as set forth in any one of claims 8 to 9, characterised in that the at least one cleaning unit is moved by the nest or by components coupled to the nest.

11. The device as set forth in any one of claims 8 to 10, characterised in that the at least one cleaning unit comprises a basic body and at least one contact module.

12. The device as set forth in claim 11, characterised in that
the at least one contact module comprises bristles.

13. The device as set forth in claim 11, characterised in that
the at least one contact module comprises an elastic plastic material, wherein a surface of the at least one contact module, which surface cleans the test contacts, has a predetermined roughness.

14. The device as set forth in any one of claims 8 to 13, characterised in that the at least one cleaning unit is exchangeable.

15. The device as set forth in any one of claims 11 to 14, characterised in that the at least one contact module is exchangeable.